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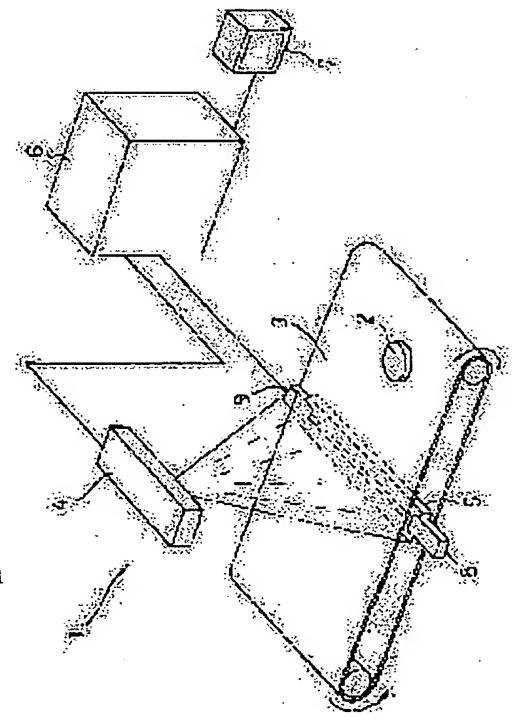
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## (54) X-RAY FOREIGN-MATTER DETECTOR

## (57)Abstract:

PROBLEM TO BE SOLVED: To provide an X-ray foreign-matter detector that can be checked always for whether or not it functions normally, without stopping a production line.

SOLUTION: This X-ray foreign-matter detector 1 is provided with a conveyor 3 for transporting an object 2 to be inspected, an X-ray generator 4 for projecting X-rays upon the object 2 transported on the conveyor 3, and an X-ray sensor 5 for detecting the transmittance of the X-rays projected upon the object 2 from the generator 4. Test pieces 8 and 9 for confirming sensitivity of this detector 1 are positioned at least one end section of the sensor 5 or the projected position of the X-rays where the object 2 is not passed in the vicinity of at least end section of the sensor 5.



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